

QUAD 2 CHANNEL MULTIPLEXER

PRELIMINARY DATA

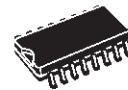
- HIGH SPEED: $t_{PD} = 4.1 \text{ ns}$ (TYP.) at $V_{CC} = 5V$
- LOW POWER DISSIPATION:
 $I_{CC} = 4 \mu A$ (MAX.) at $T_A = 25^\circ C$
- HIGH NOISE IMMUNITY:
 $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (MIN.)
- POWER DOWN PROTECTION ON INPUTS
- SYMMETRICAL OUTPUT IMPEDANCE:
 $|I_{OH}| = I_{OL} = 8 \text{ mA}$ (MIN)
- BALANCED PROPAGATION DELAYS:
 $t_{PLH} \cong t_{PHL}$
- OPERATING VOLTAGE RANGE:
 V_{CC} (OPR) = 2V to 5.5V
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 157
- IMPROVED LATCH-UP IMMUNITY
- LOW NOISE: $V_{OLP} = 0.8V$ (Max.)

DESCRIPTION

The 74VHC157 is an high-speed CMOS QUAD 2-CHANNEL MULTIPLEXER fabricated with sub-micron silicon gate and double-layer metal wiring C^2MOS technology.

It has similar high speed performance of equivalent Bipolar Schottky TTL combined with true CMOS low power dissipation.

It consists of four 2-input digital multiplexers with



M1
(Micro Package)



T
(TSSOP Package)

ORDER CODES :

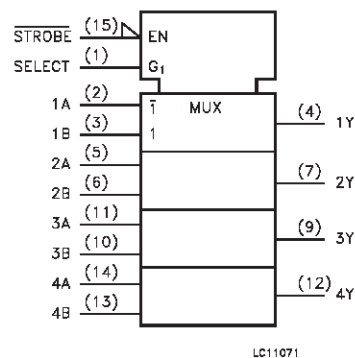
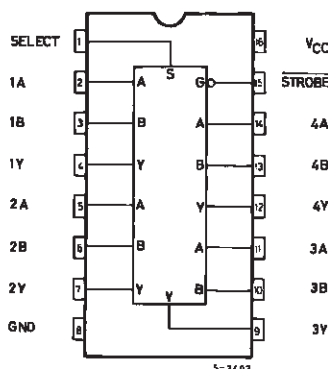
74VHC157M

74VHC157T

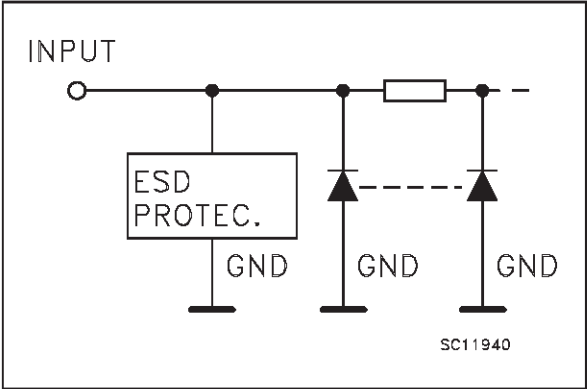
common select and strobe inputs. It is a non-inverting multiplexer. When the STROBE input is held high, selection of data is inhibited and all the outputs become low. The SELECT decoding determines whether the A or B inputs get routed to their corresponding Y outputs.

Power down protection is provided on all inputs and 0 to 7V can be accepted on inputs with no regard to the supply voltage. This device can be used to interface 5V to 3V. All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

PIN CONNECTION AND IEC LOGIC SYMBOLS



INPUT EQUIVALENT CIRCUIT



PIN DESCRIPTION

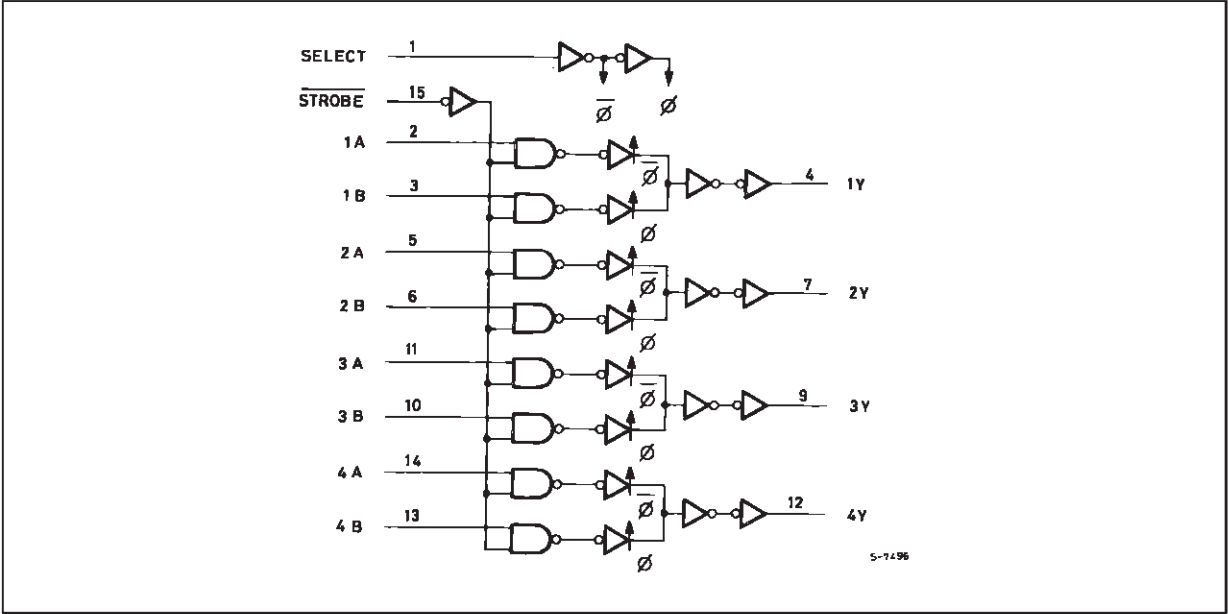
PIN No	SYMBOL	NAME AND FUNCTION
1	SELECT	Common Data Select Input
2, 5, 11, 14	1A to 4A	Data Inputs From Source A
3, 6, 10, 13	1B to 4B	Data Inputs From Source B
4, 7, 9, 12	1Y to 4Y	Multiplexer Outputs
15	$\overline{\text{STROBE}}$	Strobe Input
8	GND	Ground (0V)
16	V _{CC}	Positive Supply Voltage

TRUTH TABLE

INPUT				OUTPUT
$\overline{\text{STROBE}}$	SELECT	A	B	Y
H	X	X	X	L
L	L	L	X	L
L	L	H	X	H
L	H	X	L	L
L	H	X	H	H

X: "H" or "L"

LOGIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	-0.5 to +7.0	V
V_I	DC Input Voltage	-0.5 to +7.0	V
V_O	DC Output Voltage	-0.5 to $V_{CC} + 0.5$	V
I_{IK}	DC Input Diode Current	-20	mA
I_{OK}	DC Output Diode Current	± 20	mA
I_O	DC Output Current	± 25	mA
I_{CC} or I_{GND}	DC V_{CC} or Ground Current	± 50	mA
T_{stg}	Storage Temperature	-65 to +150	°C
T_L	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	2.0 to 5.5	V
V_I	Input Voltage	0 to 5.5	V
V_O	Output Voltage	0 to V_{CC}	V
T_{op}	Operating Temperature	-40 to +85	°C
dt/dv	Input Rise and Fall Time (see note 1) ($V_{CC} = 3.3 \pm 0.3V$) ($V_{CC} = 5.0 \pm 0.5V$)	0 to 100 0 to 20	ns/V ns/V

1) V_{IN} from 30% to 70% of V_{CC}

DC SPECIFICATIONS

Symbol	Parameter	Test Conditions		Value					Unit	
		V _{CC} (V)		T _A = 25 °C			-40 to 85 °C			
				Min.	Typ.	Max.	Min.	Max.		
V _{IH}	High Level Input Voltage	2.0		1.5			1.5		V	
		3.0 to 5.5		0.7V _{CC}			0.7V _{CC}			
V _{IL}	Low Level Input Voltage	2.0				0.5		0.5	V	
		3.0 to 5.5				0.3V _{CC}		0.3V _{CC}		
V _{OH}	High Level Output Voltage	2.0	V _I ^(*) = V _{IH} or V _{IL}	I _O = -50 μA	1.9	2.0		1.9		V
		3.0		I _O = -50 μA	2.9	3.0		2.9		
		4.5		I _O = -50 μA	4.4	4.5		4.4		
		3.0		I _O = -4 mA	2.58			2.48		
		4.5		I _O = -8 mA	3.94			3.8		
V _{OL}	Low Level Output Voltage	2.0	V _I ^(*) = V _{IH} or V _{IL}	I _O = 50 μA		0.0	0.1		0.1	V
		3.0		I _O = 50 μA		0.0	0.1		0.1	
		4.5		I _O = 50 μA		0.0	0.1		0.1	
		3.0		I _O = 4 mA			0.36		0.44	
		4.5		I _O = 8 mA			0.36		0.44	
I _I	Input Leakage Current	0 to 5.5	V _I = 5.5V or GND				±0.1		±1.0	μA
I _{CC}	Quiescent Supply Current	5.5	V _I = V _{CC} or GND				4		40	μA

(*) All outputs loaded.

AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3$ ns)

Symbol	Parameter	Test Condition			Value					Unit
		V _{CC} (V)	C _L (pF)		T _A = 25 °C			-40 to 85 °C		
					Min.	Typ.	Max.	Min.	Max.	
t _{PLH} t _{PHL}	Propagation Delay Time A, B to Y	3.3 ^(*)	15			6.2	9.7	1.0	11.5	ns
		3.3 ^(*)	50			8.7	13.2	1.0	15.0	
		5.0 ^(**)	15			4.1	6.4	1.0	7.5	
		5.0 ^(**)	50			5.6	8.4	1.0	9.5	
t _{PLH} t _{PHL}	Propagation Delay Time SELECT to Y	3.3 ^(*)	15			8.4	13.2	1.0	15.5	ns
		3.3 ^(*)	50			10.9	16.7	1.0	19.0	
		5.0 ^(**)	15			5.3	8.1	1.0	9.5	
		5.0 ^(**)	50			6.8	10.1	1.0	11.5	
t _{PLH} t _{PHL}	Propagation Delay Time STROBE to Y	3.3 ^(*)	15			8.7	13.6	1.0	16.0	ns
		3.3 ^(*)	50			11.2	17.1	1.0	19.5	
		5.0 ^(**)	15			5.6	8.6	1.0	10.0	
		5.0 ^(**)	50			7.1	10.6	1.0	12.0	

(*) Voltage range is 3.3V ± 0.3V

(**) Voltage range is 5V ± 0.5V

CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions	Value					Unit
			T _A = 25 °C			-40 to 85 °C		
			Min.	Typ.	Max.	Min.	Max.	
C _{IN}	Input Capacitance			4	10		10	pF
C _{PD}	Power Dissipation Capacitance (note 1)			20				pF

1) C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation. $I_{CC(opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4$ (per Channel)

DYNAMIC SWITCHING CHARACTERISTICS

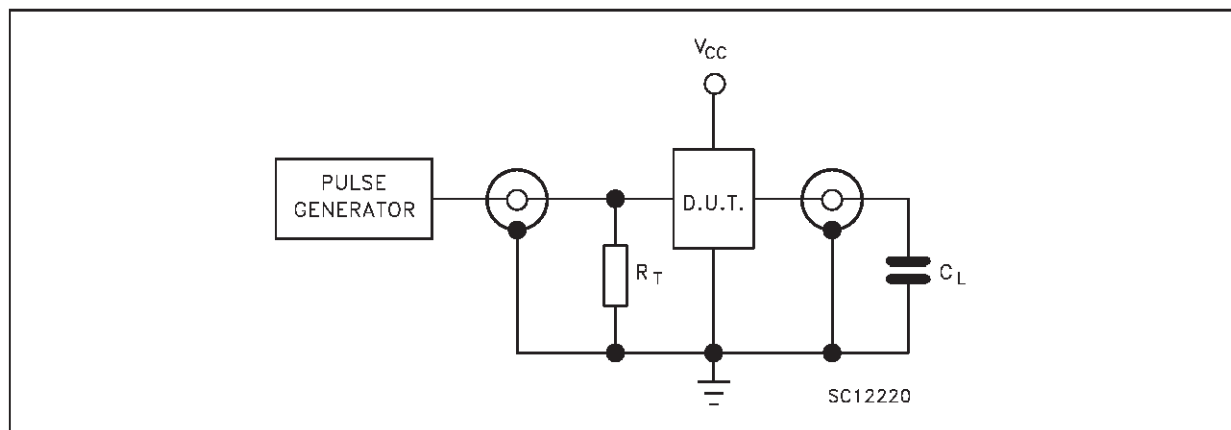
Symbol	Parameter	Test Conditions		Value					Unit
		V _{CC} (V)		T _A = 25 °C			-40 to 85 °C		
				Min.	Typ.	Max.	Min.	Max.	
V _{OLP}	Dynamic Low Voltage	5.0	C _L = 50 pF		0.3	0.8			V
V _{OLV}	Quiet Output (note 1, 2)			-0.8	-0.3				
V _{IHD}	Dynamic High Voltage Input (note 1, 3)	5.0		3.5					
V _{ILD}	Dynamic Low Voltage Input (note 1, 3)	5.0				1.5			

1) Worst case package.

2) Max number of outputs defined as (n). Data inputs are driven 0V to 5.0V, (n-1) outputs switching and one output at GND.

3) Max number of data inputs (n) switching. (n-1) switching 0V to 5.0V. Inputs under test switching: 5.0V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f=1MHz.

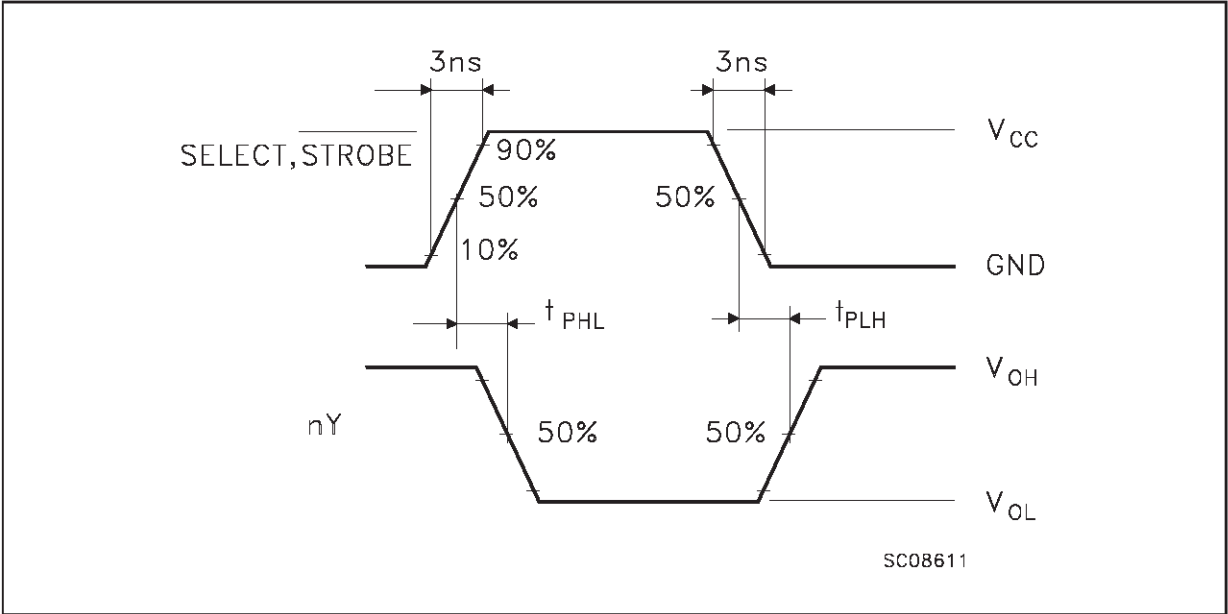
TEST CIRCUIT



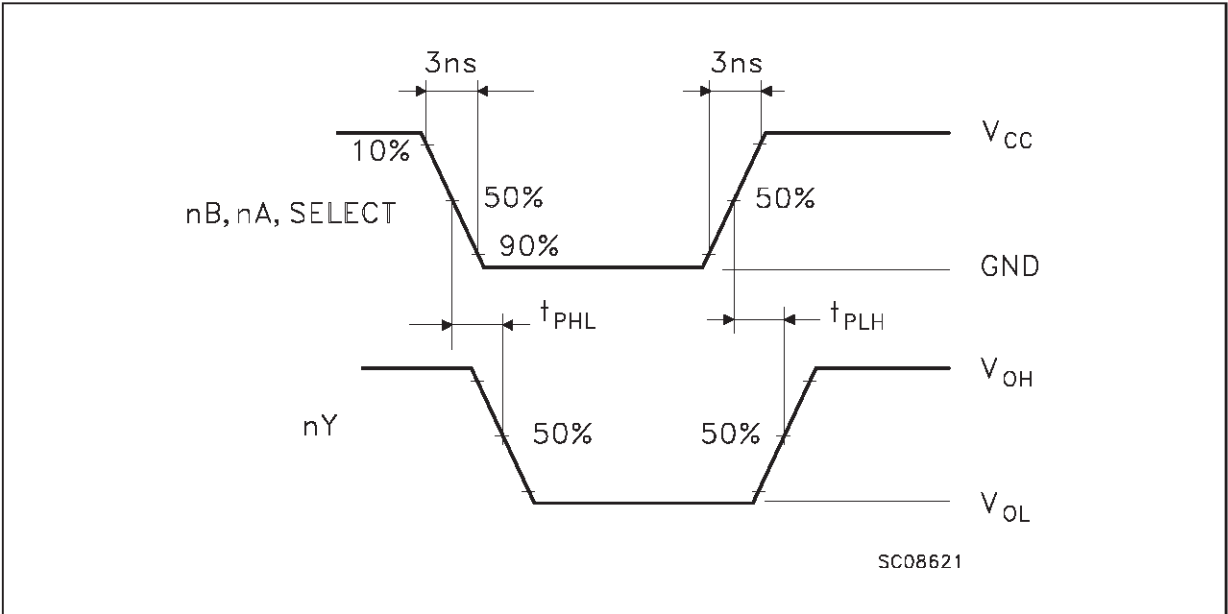
C_L = 15/50 pF or equivalent (includes jig and probe capacitance)

R_T = Z_{OUT} of pulse generator (typically 50Ω)

WAVEFORM 1: PROPAGATION DELAYS FOR INVERTING CONDITIONS

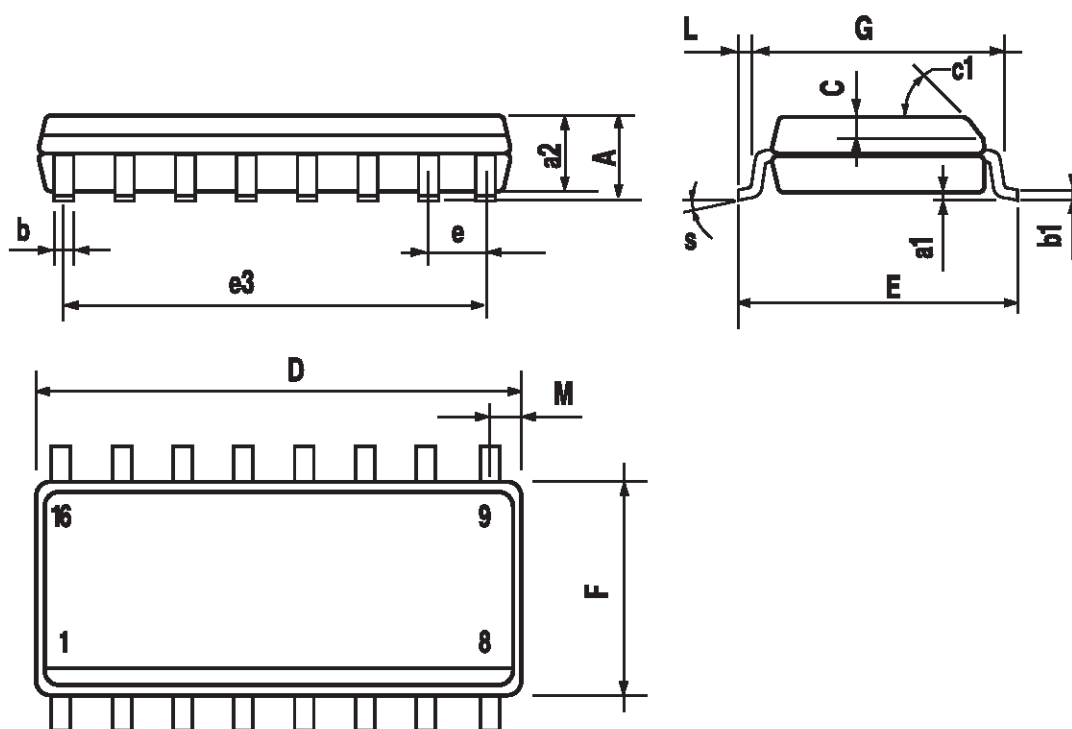


WAVEFORM 2: PROPAGATION DELAYS FOR NON-INVERTING CONDITIONS



SO-16 MECHANICAL DATA

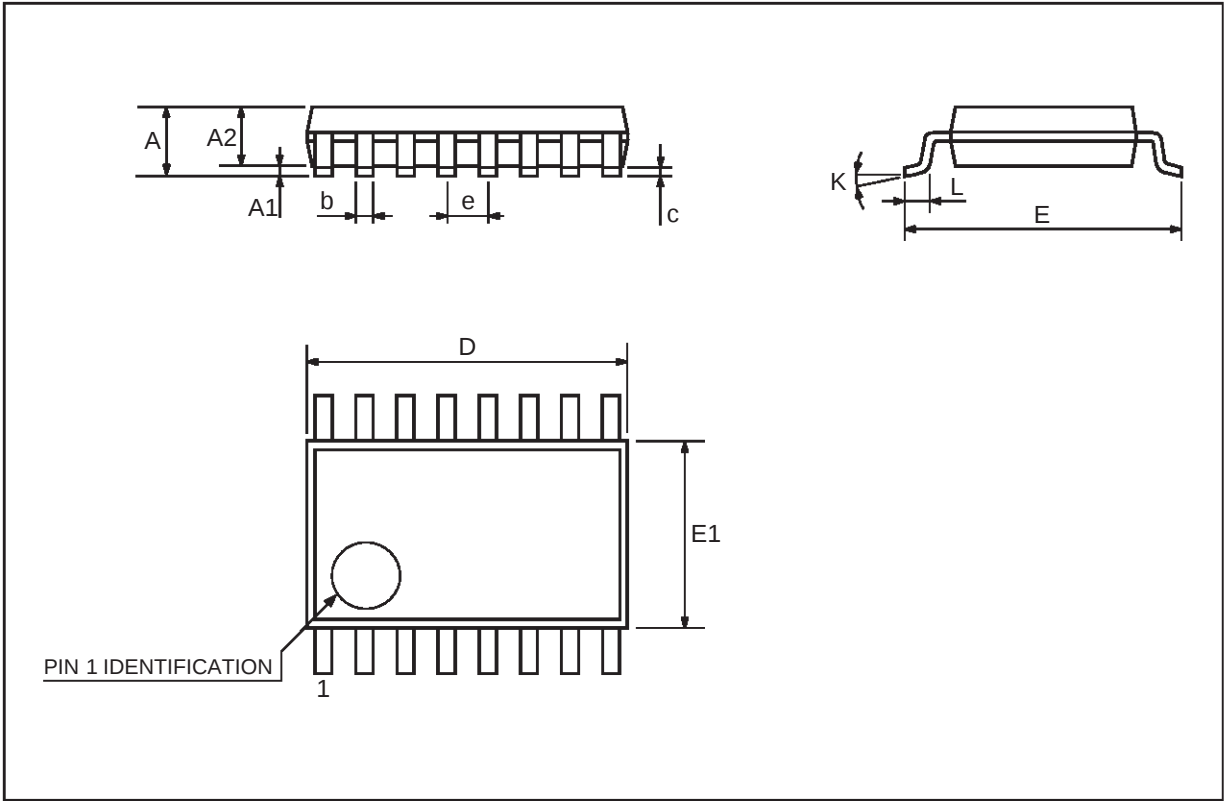
DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.2	0.004		0.007
a2			1.65			0.064
b	0.35		0.46	0.013		0.018
b1	0.19		0.25	0.007		0.010
C		0.5			0.019	
c1	45 (typ.)					
D	9.8		10	0.385		0.393
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		8.89			0.350	
F	3.8		4.0	0.149		0.157
G	4.6		5.3	0.181		0.208
L	0.5		1.27	0.019		0.050
M			0.62			0.024
S	8 (max.)					



P013H

TSSOP16 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.1			0.433
A1	0.05	0.10	0.15	0.002	0.004	0.006
A2	0.85	0.9	0.95	0.335	0.354	0.374
b	0.19		0.30	0.0075		0.0118
c	0.09		0.20	0.0035		0.0079
D	4.9	5	5.1	0.193	0.197	0.201
E	6.25	6.4	6.5	0.246	0.252	0.256
E1	4.3	4.4	4.48	0.169	0.173	0.176
e		0.65 BSC			0.0256 BSC	
K	0°	4°	8°	0°	4°	8°
L	0.50	0.60	0.70	0.020	0.024	0.028



Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specification mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics.

The ST logo is a registered trademark of STMicroelectronics

© 1998 STMicroelectronics – Printed in Italy – All Rights Reserved
STMicroelectronics GROUP OF COMPANIES

Australia - Brazil - Canada - China - France - Germany - Italy - Japan - Korea - Malaysia - Malta - Mexico - Morocco - The Netherlands -
Singapore - Spain - Sweden - Switzerland - Taiwan - Thailand - United Kingdom - U.S.A.

<http://www.st.com>